

### **MOSFET**

#### CoolSiC™ MOSFET 650 V G2

Built on Infineon's robust 2<sup>nd</sup> generation Silicon Carbide trench technology, the 650 V CoolSiC<sup>™</sup> MOSFET delivers unparalleled performance, superior reliability, and great ease of use. It enables cost effective, highly efficient, and simplified designs to fulfill the ever-growing system and market needs.

#### **Features**

- Ultra-low switching losses
- Benchmark gate threshold voltage, V<sub>GS(th)</sub> = 4.5 V
- Robust against parasitic turn-on even with 0 V turn-off gate voltage
- Flexible driving voltage and compatible with bipolar driving scheme
- Robust body diode operation under hard commutation events
- .XT interconnection technology for best-in-class thermal performance

#### **Benefits**

- · Enables high efficiency and high power density designs
- Facilitates great ease of use and integration
- Provides the best price performance ratio compared to Industry's most ambitious roadmaps
- Reduces the size, weight and bill of materials of the systems
- Enhances system robustness and reliability

#### Potential applications

- SMPS
- · Solar PV inverters
- · Energy storage and battery formation
- UPS
- · EV charging infrastructure
- Motor drives

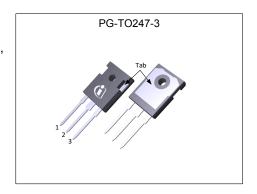
#### **Product validation**

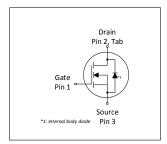
Fully qualified according to JEDEC for Industrial Applications



Parameter	Value	Unit
$V_{\rm DSS}$ over full $T_{\rm j,range}$	650	V
R <sub>DS(on),typ</sub>	20	mΩ
R <sub>DS(on),max</sub>	24	mΩ
$Q_{G,typ}$	57	nC
I <sub>D,pulse</sub>	290	A
Q <sub>oss</sub> @ 400 V	108	nC
E <sub>oss</sub> @ 400 V	14.7	μJ

Type / Ordering Code	Package	Marking	Related Links
IMW65R020M2H	PG-TO247-3	65R020M2	see Appendix A













Rev. 2.2, 2024-03-05

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1 Maximum ratings at  $T_j = 25$  °C, unless otherwise specified.

Note: for optimum lifetime and reliability, Infineon recommends operating conditions that do not exceed 80% of the maximum ratings stated in this datasheet.

Table 2 Maximum ratings

Danamatan	Ol		Value	s	11!4	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Continuous DC drain current <sup>1)</sup>	I <sub>DDC</sub>	-	-	83 58	А	T <sub>C</sub> = 25 °C T <sub>C</sub> = 100 °C
Peak drain current <sup>2)</sup>	I <sub>DM</sub>	-	-	290	Α	T <sub>C</sub> = 25 °C, V <sub>GS</sub> = 18 V
Avalanche energy, single pulse	<b>E</b> <sub>AS</sub>	-	-	272	mJ	$I_D = 10.2 \text{ A}, V_{DD} = 50 \text{ V}; \text{ see table } 11$
Avalanche energy, repetitive	<b>E</b> AR	-	-	1.36	mJ	$I_{\rm D}$ = 10.2 A, $V_{\rm DD}$ = 50 V; see table 11
Avalanche current, single pulse	I <sub>AS</sub>	-	-	10.2	Α	-
MOSFET dv/dt ruggedness	dv/dt	-	-	200	V/ns	V <sub>DS</sub> = 0400 V
Gate source voltage (static) <sup>3)</sup>	V <sub>GS</sub>	-7	-	23	V	-
Gate source voltage (transient)	V <sub>GS</sub>	-10	-	25	V	$t_p \le 500 \text{ ns}, \text{ duty cycle} \le 1 \%$
Power dissipation	P <sub>tot</sub>	-	-	273	W	T <sub>C</sub> = 25 °C
Storage temperature	T <sub>stg</sub>	-55	-	150	°C	-
Operating junction temperature	T <sub>j</sub>	-55	-	175	°C	-
Mounting torque	-	-	-	60	Ncm	M3 and M3.5 screws
Continuous reverse drain current <sup>1)</sup>	I <sub>SDC</sub>	-	-	83 52.3	А	V <sub>GS</sub> = 18 V, T <sub>C</sub> = 25 °C V <sub>GS</sub> = 0 V, T <sub>C</sub> = 25 °C
Peak reverse drain current <sup>2)</sup>	I <sub>SM</sub>	-	-	290 88	А	$T_{\rm C}$ = 25 °C, $t_{\rm p}$ ≤ 250 ns $T_{\rm C}$ = 25 °C
Insulation withstand voltage	V <sub>ISO</sub>		-	n.a.	V	$V_{\rm rms}$ , $T_{\rm C}$ = 25 °C, $t$ = 1 min

<sup>&</sup>lt;sup>1)</sup> Limited by  $T_{\rm J,max}$ <sup>2)</sup> Pulse width  $t_{\rm pulse}$  limited by  $T_{\rm j,max}$ .
<sup>3)</sup> The maximum gate-source voltage in the application design should be in accordance to IPC-9592B.



### 2 Thermal characteristics

**Table 3** Thermal characteristics

Developed	Cymphal	Values			11:4	Note / Took Condition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Thermal resistance, junction - case	R <sub>th(j-c)</sub>	-	-	0.55	°C/W	Not subject to production test. Parameter verified by design/characterization according to JESD51-14.	
Soldering temperature, wavesoldering only allowed at leads	T <sub>sold</sub>	-	-	260	°C	1.6 mm (0.063 in.) from case for 10 s	

# 3 Operating range

Table 4 Operating range

Doromotor	Cymbol	Values			Unit	Nata / Tast Candition
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Recommended turn-on voltage	V <sub>GS(on)</sub>	-	18	-	V	-
Recommended turn-off voltage	V <sub>GS(off)</sub>	-	0	-	V	-



# 4 Electrical characteristics at $T_j = 25$ °C, unless otherwise specified

#### Table 5 Static characteristics

Davamatav	Correspond	Values				Note / Took Condition
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Drain-source voltage	V <sub>DSS</sub>	650	-	-	V	$V_{\rm GS}$ = 0 V, $I_{\rm D}$ = 0.95 mA
Gate threshold voltage <sup>1)</sup>	V <sub>GS(th)</sub>	3.5	4.5	5.6	V	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 9.5  \rm mA$
Zero gate voltage drain current	I <sub>DSS</sub>	-	1 3	75 -	μА	$V_{\rm DS} = 650 \text{ V}, V_{\rm GS} = 0 \text{ V}, T_{\rm j} = 25 ^{\circ}\text{C}$ $V_{\rm DS} = 650 \text{ V}, V_{\rm GS} = 0 \text{ V}, T_{\rm j} = 175 ^{\circ}\text{C}$
Gate-source leakage current	I <sub>GSS</sub>	-	-	100	nA	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V
Drain-source on-state resistance	R <sub>DS(on)</sub>	- - - -	26 20 18 33	- 24 - -	mΩ	$V_{\rm GS}$ = 15 V, $I_{\rm D}$ = 46.9 A, $T_{\rm j}$ = 25 °C $V_{\rm GS}$ = 18 V, $I_{\rm D}$ = 46.9 A, $T_{\rm j}$ = 25 °C $V_{\rm GS}$ = 20 V, $I_{\rm D}$ = 46.9 A, $T_{\rm j}$ = 25 °C $V_{\rm GS}$ = 18 V, $I_{\rm D}$ = 46.9 A, $T_{\rm j}$ =175 °C
Internal gate resistance	<b>R</b> <sub>G,int</sub>	-	2.5	-	Ω	f = 1 MHz

 $<sup>^{1)}</sup>$  Tested after 1 ms pulse at V<sub>GS</sub> = +20 V. "Linear mode" operation is not recommended. For assessment of potential "linear mode" operation, please contact Infineon sales office.



#### Table 6 **Dynamic characteristics**

External parasitic elements (PCB layout) influence switching behavior significantly. Stray inductances and coupling capacitances must be minimized.

For layout recommendations please use provided application notes or contact Infineon sales office.

Damanastan	Cyronia al		Values			Nata / Tank One distant	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Input capacitance	C <sub>iss</sub>	-	2038	-	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, f = 250 \text{ kHz}$	
Reverse transfer capacitance	C <sub>rss</sub>	-	11.5	-	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, f = 250 \text{ kHz}$	
Output capacitance <sup>1)</sup>	Coss	-	151	197	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, f = 250 \text{ kHz}$	
Output charge <sup>1)</sup>	Qoss	-	108	141	nC	calculation based on Coss	
Effective output capacitance, energy related <sup>2)</sup>	C <sub>o(er)</sub>	-	183	-	pF	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 0400 V	
Effective output capacitance, time related <sup>3)</sup>	C <sub>o(tr)</sub>	-	271	-	pF	$I_D$ = constant, $V_{GS}$ = 0 V, $V_{DS}$ = 0400 V	
Turn-on delay time	$t_{ m d(on)}$	-	29	-	ns	$V_{\rm DD} = 400 \text{ V}, \ V_{\rm GS} = 0/18 \text{ V}, \ I_{\rm D} = 46.9 \text{ A}, \ R_{\rm G,ext} = 1.8 \ \Omega;$ see table 10	
Rise time	t <sub>r</sub>	-	16	-	ns	$V_{\rm DD} = 400 \text{ V}, \ V_{\rm GS} = 0/18 \text{ V}, \ I_{\rm D} = 46.9 \text{ A}, \ R_{\rm G,ext} = 1.8 \ \Omega;$ see table 10	
Turn-off delay time	$t_{ m d(off)}$	-	19	-	ns	$V_{\rm DD} = 400 \text{ V}, \ V_{\rm GS} = 0/18 \text{ V}, \ I_{\rm D} = 46.9 \text{ A}, \ R_{\rm G,ext} = 1.8 \ \Omega;$ see table 10	
Fall time	t <sub>f</sub>	-	7.0	-	ns	$V_{\rm DD} = 400 \text{ V}, V_{\rm GS} = 0/18 \text{ V}, I_{\rm D} = 46.9 \text{ A}, R_{\rm G,ext} = 1.8 \Omega;$ see table 10	
Turn-ON switching losses <sup>4)</sup>	E <sub>on</sub>	-	506	-	μJ	$V_{\rm DD} = 400 \text{ V}, V_{\rm GS} = 0/18 \text{ V}, I_{\rm D} = 46.9 \text{ A}, R_{\rm G,ext} = 1.8 \Omega$	
Turn-OFF switching losses <sup>4)</sup>	E <sub>off</sub>	-	90	-	μJ	$V_{\rm DD} = 400 \text{ V}, V_{\rm GS} = 0/18 \text{ V}, I_{\rm D} = 46.9 \text{ A}, R_{\rm G,ext} = 1.8 \Omega$	
Total switching losses <sup>4)</sup>	E <sub>tot</sub>	-	596	-	μJ	$V_{DD} = 400 \text{ V}, V_{GS} = 0/18 \text{ V},$ $I_D = 46.9 \text{ A}, R_{G,ext} = 1.8 \Omega$	

Table 7 **Gate charge characteristics** 

Parameter	Cyronhad		Values			Nata / Tarak O and History
	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Plateau gate to source charge	Q <sub>GS(pl)</sub>	-	15	-	nC	$V_{DD} = 400 \text{ V}, I_D = 46.9 \text{ A}, V_{GS} = 0 \text{ to } 18 \text{ V}$
Gate to drain charge	$Q_{GD}$	-	11	-	nC	$V_{DD} = 400 \text{ V}, I_D = 46.9 \text{ A}, V_{GS} = 0 \text{ to } 18 \text{ V}$
Total gate charge	Q <sub>G</sub>	-	57	-	nC	$V_{DD} = 400 \text{ V}, I_D = 46.9 \text{ A}, V_{GS} = 0 \text{ to } 18 \text{ V}$

 $<sup>^{1)}</sup>$  Maximum specification is defined by calculated six sigma upper confidence bound  $^{2)}$   $C_{o(er)}$  is a fixed capacitance that gives the same stored energy as  $C_{\rm oss}$  while  $V_{\rm DS}$  is rising from 0 to 400 V.  $^{3)}$   $C_{\rm o(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{\rm oss}$  while  $V_{\rm DS}$  is rising from 0 to 400 V.  $^{4)}$  MOSFET used in half-bridge configuration without external diode

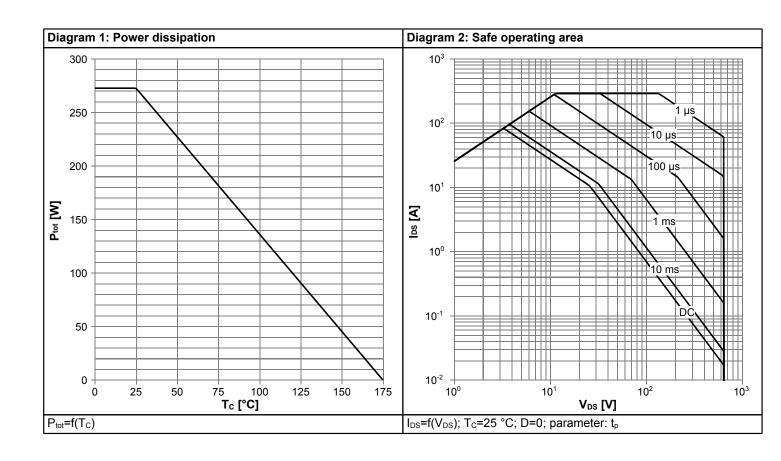


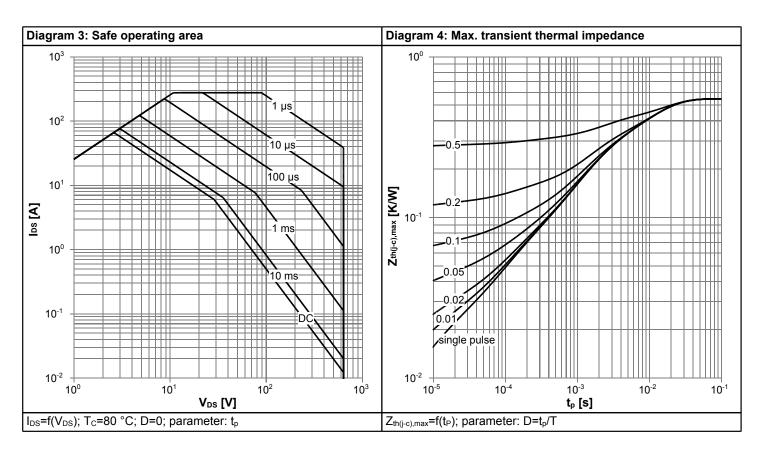
### Table 8 Reverse diode characteristics

Parameter	Cymbal	Values			Unit	Note / Test Condition	
raiailietei	Symbol	Min.	Тур.	Max.	Ullit	Note / Test Condition	
Drain-source reverse voltage	V <sub>SD</sub>	-	4.3	-	V	$V_{GS} = 0 \text{ V}, I_{S} = 46.9 \text{ A}, T_{j} = 25 \text{ °C}$	
MOSFET forward recovery time	t <sub>fr</sub>	-	37.2	-	ns	$V_{\rm DD}$ = 400 V, $I_{\rm S}$ = 46.9 A, d $i_{\rm S}/dt$ = 1000 A/ $\mu$ s; see table 9	
MOSFET forward recovery charge <sup>1)</sup>	Q <sub>fr</sub>	-	167	-	nC	$V_{\rm DD}$ = 400 V, $I_{\rm S}$ = 46.9 A, $di_{\rm S}/dt$ = 1000 A/µs; see table 9	
MOSFET peak forward recovery current	I <sub>frm</sub>	-	9	-	А	$V_{\rm DD}$ = 400 V, $I_{\rm S}$ = 46.9 A, $di_{\rm S}/dt$ = 1000 A/µs; see table 9	

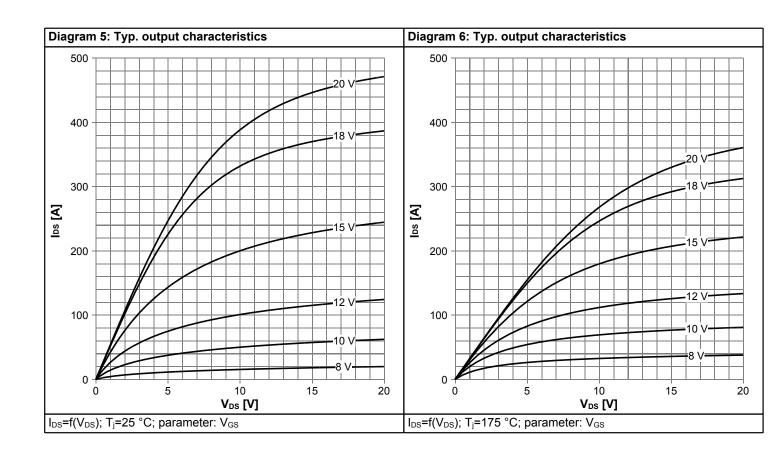


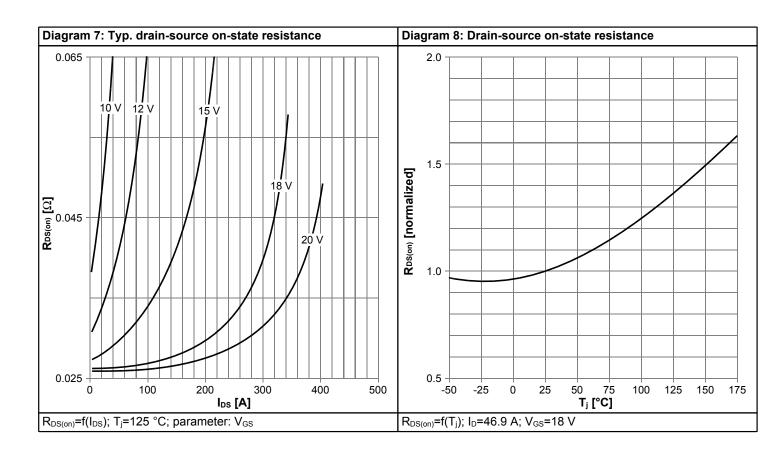
# 5 Electrical characteristics diagrams



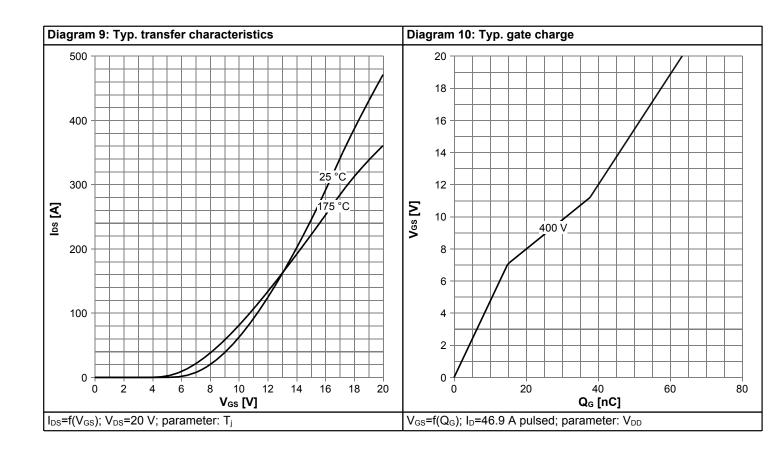


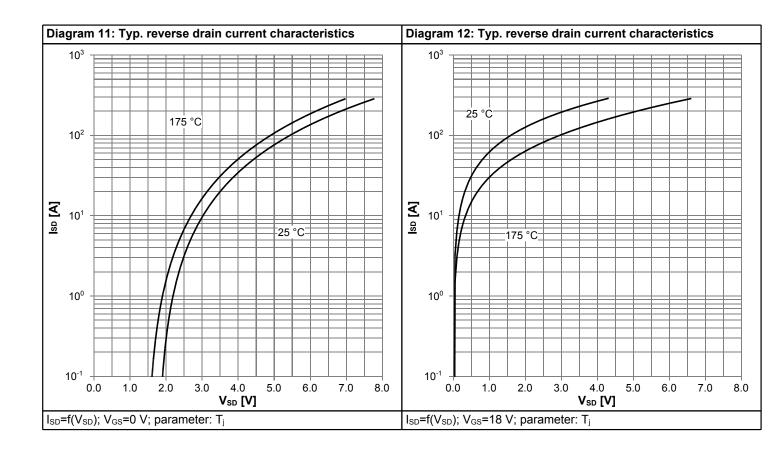




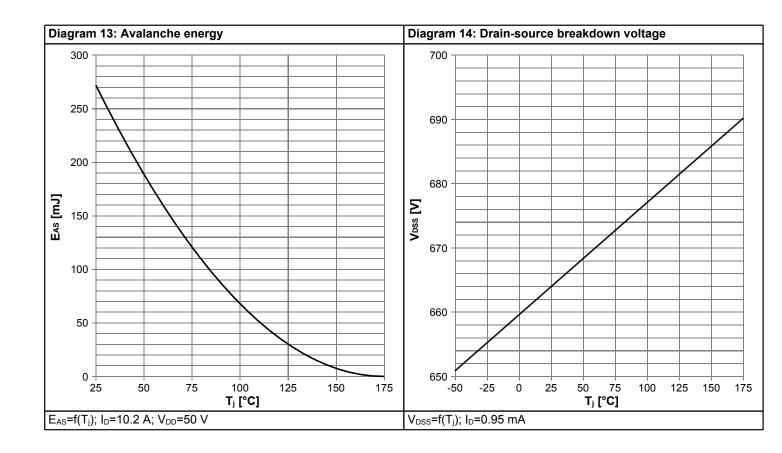


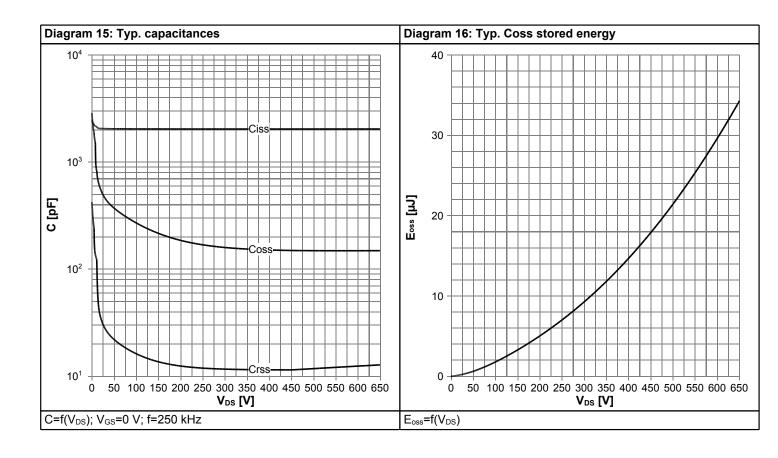




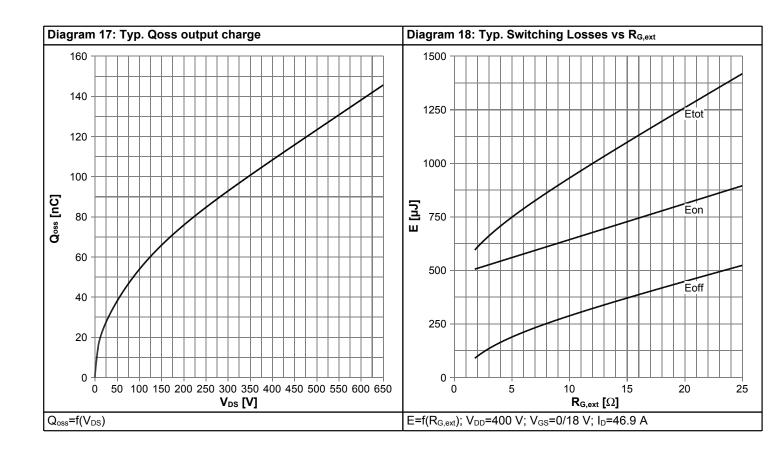


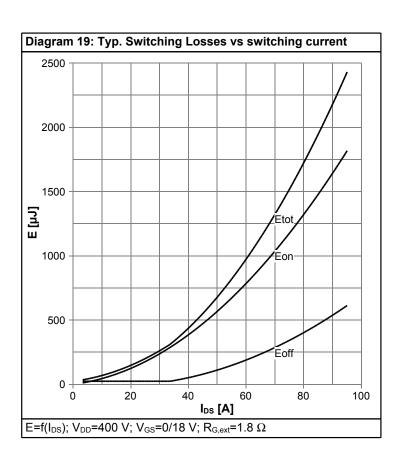














#### 6 Test Circuits

Table 9 Body diode characteristics

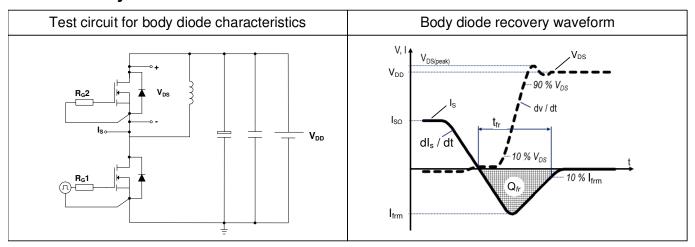


Table 10 Switching times

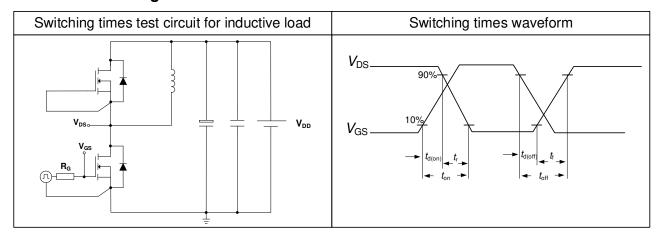
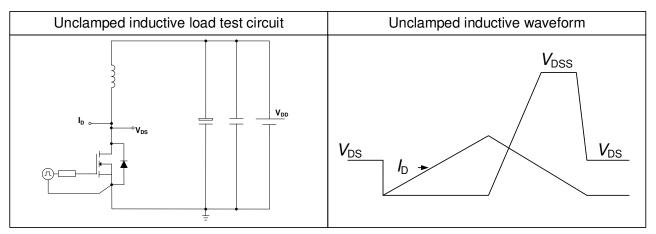
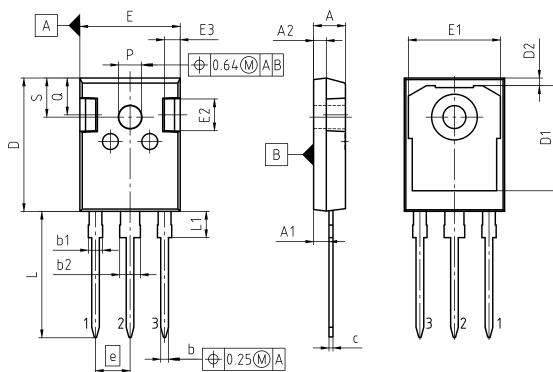


Table 11 Unclamped inductive load





# 7 Package Outlines



PACKAGE - GROUP NUMBER:	PG-TO247-3-U06						
DIMENSIONS	MILLIMETERS						
DIMENSIONS	MIN.	MAX.					
Α	4.83	5.21					
A1	2.27	2.54					
A2	1.85	2.16					
b	1.07	1.33					
b1	1.90	2.41					
b2	2.87	3.38					
С	0.55	0.68					
D	20.80	21.10					
D1	16.25	17.65					
D2	0.95	1.35					
E	15.70	16.13					
E1	13.10	14.15					
E2	3.68	5.10					
E3	1.00	2.60					
е	5.44						
N	3						
L	19.80	20.32					
L1	4.10	4.47					
øΡ	3.50	3.70					
Q	5.49	6.00					
S	6.04	6.30					

NOTE:

DIMENSIONS DO NOT INCLUDE MOLDFLASH; PROTRUSION OR GATE BURRS

Figure 1 Outline PG-TO247-3, dimensions in mm



# 8 Appendix A

#### Table 12 Related Links

- IFX CoolSiC CoolSiC™ MOSFET 650 V G2 Webpage: www.infineon.com
- IFX CoolSiC CoolSiC™ MOSFET 650 V G2 application note: www.infineon.com
- IFX CoolSiC CoolSiC™ MOSFET 650 V G2 simulation model: www.infineon.com
- IFX Design tools: www.infineon.com



#### **Revision History**

IMW65R020M2H

Revision: 2024-03-05, Rev. 2.2

Previous Revision

1 TOVIOUS TREVISION					
Revision	Date	Subjects (major changes since last revision)			
2.0	2023-11-02	Release of final version			
2.1	2024-02-29	updated simulation model; included Eon and Eoff data and diagrams			
2.2	2024-03-05	minor layout changes			

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